

<b>Notice of References Cited</b>	Application/Control No. 10/775,888		Applicant(s)/Patent Under Reexamination ENDERMANN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0024018	02-2004	Kanikanti et al.	514/312
	B	US-			
	C	US-			
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	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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